

MOSFET

StrongIRFET™ 2 Power-Transistor

Features

- Optimized for a wide range of applications
 N-Channel, normal level
 100% avalanche tested

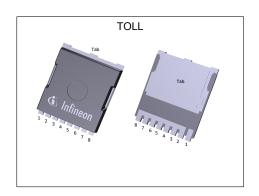
- Pb-free lead plating; RoHS compliant
 Halogen-free according to IEC61249-2-21

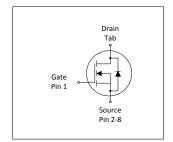
Product validation

Qualified according to JEDEC Standard

Table 1 **Key Performance Parameters**

i da i di								
Parameter	Value	Unit						
$V_{ extsf{DS}}$	80	V						
$R_{DS(on),max}$	1.23	mΩ						
I _D	351	A						
Qoss	199	nC						
Q _G	170	nC						











Type / Ordering Code	Package	Marking	Related Links
IPT012N08NF2S	PG-HSOF-8	012N08NS	-



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1 Maximum ratings at T_A =25 °C, unless otherwise specified

Table 2 Maximum ratings

Danamastan	Symbol	Values				N
Parameter		Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current ¹⁾	I D	- - -	- - -	351 248 211 39	A	V_{GS} =10 V, T_{C} =25 °C V_{GS} =10 V, T_{C} =100 °C V_{GS} =6 V, T_{C} =100 °C V_{GS} =10V, T_{A} =25°C, R_{thJA} =40°C/W ²)
Pulsed drain current ³⁾	I _{D,pulse}	-	-	1404	Α	<i>T</i> _A =25 °C
Avalanche energy, single pulse ⁴⁾	E AS	-	-	374	mJ	$I_{\rm D}$ =150 A, $R_{\rm GS}$ =25 Ω
Gate source voltage	V _{GS}	-20	-	20	V	-
Power dissipation	P _{tot}	-	-	300 3.8	W	T _C =25 °C T _A =25 °C, R _{thJA} =40 °C/W ²⁾
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$	-55	-	175	°C	-

2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition
Thermal resistance, junction - case	R _{thJC}	-	-	0.5	°C/W	-
Thermal resistance, junction - ambient, 6 cm² cooling area²)		-	-	40	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	R _{thJA}	-	-	62	°C/W	-

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions. $^{2)}$ Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

4) See Diagram 13 for more detailed information



3 Electrical characteristics

at T_j=25 °C, unless otherwise specified

Table 4 Static characteristics

Damanatan	0		Values			N
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V _{(BR)DSS}	80	-	-	V	V _{GS} =0 V, I _D =1 mA
Gate threshold voltage	V _{GS(th)}	2.2	3.0	3.8	V	V _{DS} =V _{GS} , I _D =267 μA
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	V _{DS} =80 V, V _{GS} =0 V, T _j =25 °C V _{DS} =80 V, V _{GS} =0 V, T _j =125 °C
Gate-source leakage current	I _{GSS}	-	10	100	nA	V _{GS} =20 V, V _{DS} =0 V
Drain-source on-state resistance	R _{DS(on)}	-	1.1 1.3	1.23 1.8	mΩ	V _{GS} =10 V, I _D =150 A V _{GS} =6 V, I _D =75 A
Gate resistance	R _G	-	1.4	-	Ω	-
Transconductance ¹⁾	g fs	135	-	-	S	$ V_{DS} \ge 2 I_D R_{DS(on)max}, I_D=100 A$

Table 5 Dynamic characteristics

Damamatan	O make at		Values			N (7 10 10)
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	Ciss	-	12000	-	pF	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz
Output capacitance	Coss	-	1900	-	pF	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz
Reverse transfer capacitance	Crss	-	83	-	pF	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	25	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω
Rise time	t _r	-	72	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω
Turn-off delay time	$t_{ m d(off)}$	-	72	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω
Fall time	t _f	-	44	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω

Table 6 Gate charge characteristics²⁾

Davamatar	Cumbal	Values			11:4	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q _{gs}	-	53	-	nC	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Gate charge at threshold	$Q_{g(th)}$	-	36	-	nC	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Gate to drain charge	Q_{gd}	-	35	-	nC	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Switching charge	Qsw	-	53	-	nC	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Gate charge total ¹⁾	Q g	-	170	255	nC	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Gate plateau voltage	V _{plateau}	-	4.4	-	V	V_{DD} =40 V, I_{D} =100 A, V_{GS} =0 to 10 V
Output charge	Qoss	-	199	-	nC	V _{DS} =40 V, V _{GS} =0 V

 $^{^{1)}}$ Defined by design. Not subject to production test. $^{2)}$ See "Gate charge waveforms" for parameter definition

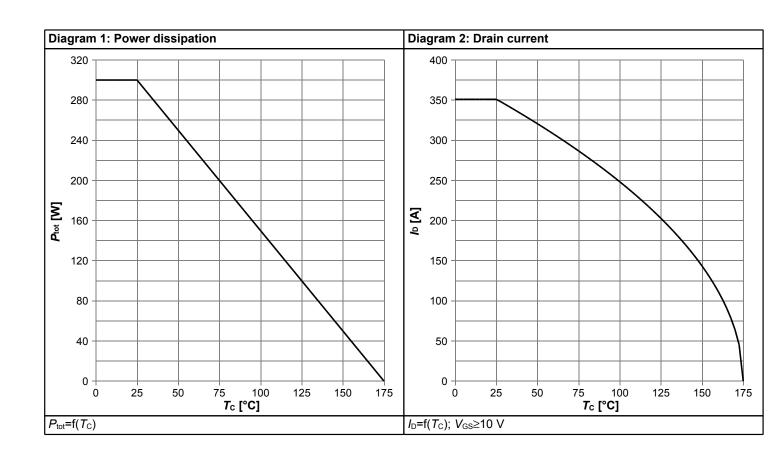


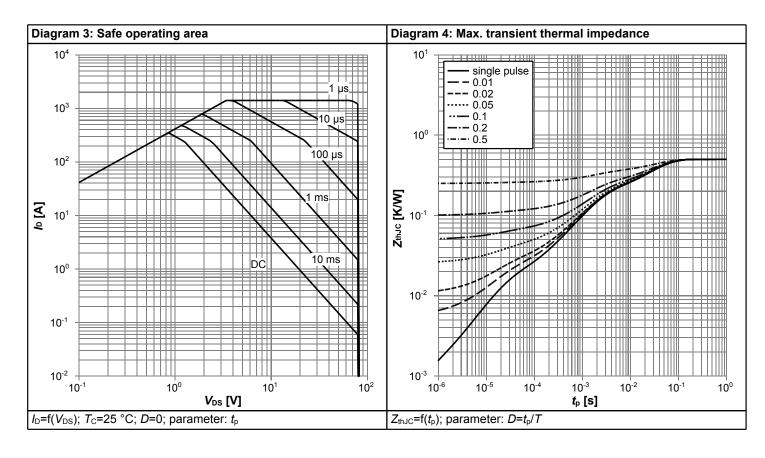
Table 7 Reverse diode

Dougnatou	Cumbal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	214	Α	<i>T</i> _C =25 °C	
Diode pulse current	I _{S,pulse}	-	-	1404	Α	T _C =25 °C	
Diode forward voltage	V _{SD}	-	0.85	1.2	V	V _{GS} =0 V, I _F =100 A, T _j =25 °C	
Reverse recovery time	t _{rr}	-	48	-	ns	V _R =40 V, I _F =100 A, di _F /dt=500 A/μs	
Reverse recovery charge	Qrr	-	383	-	nC	V _R =40 V, I _F =100 A, di _F /dt=500 A/μs	

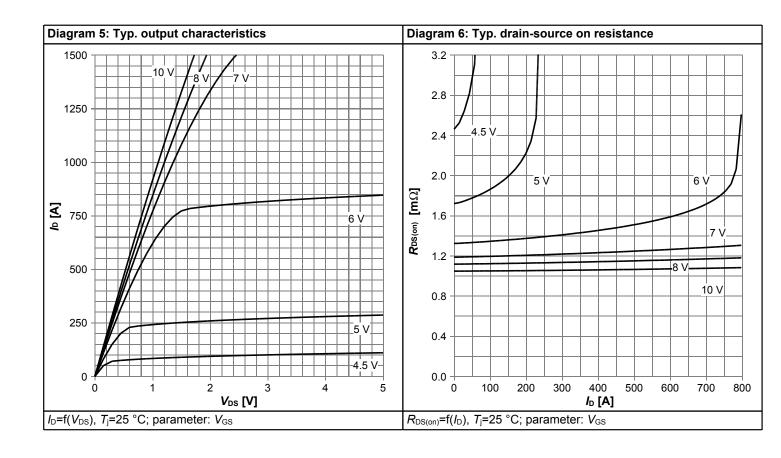


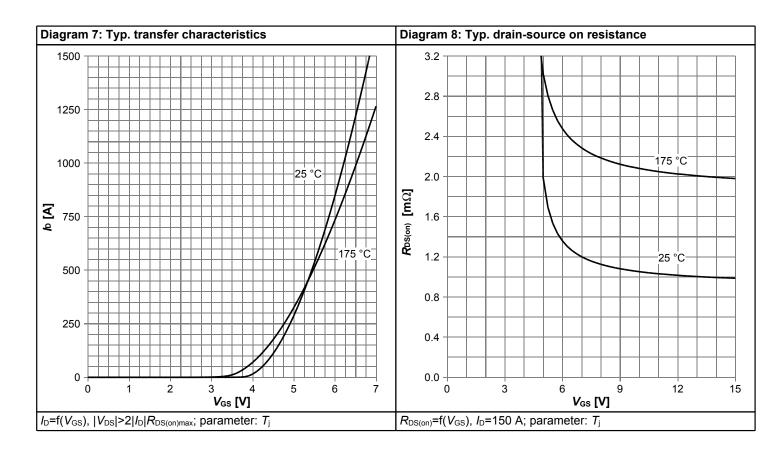
4 Electrical characteristics diagrams



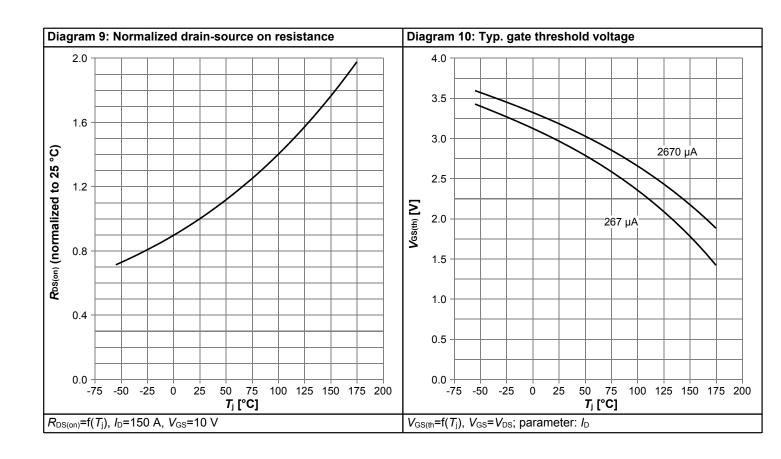


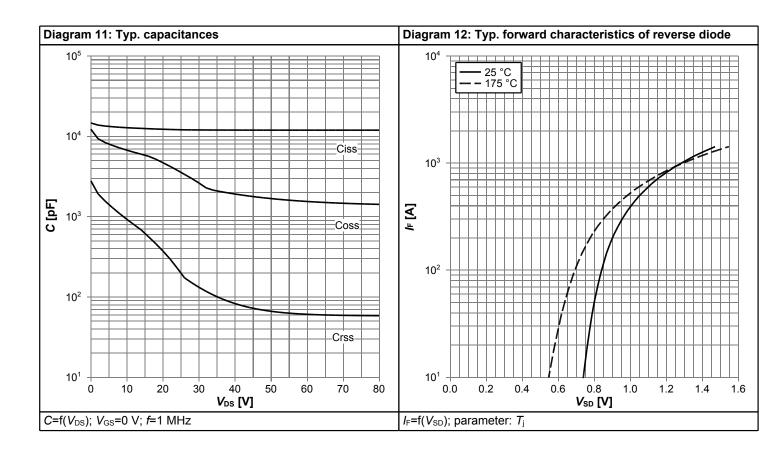




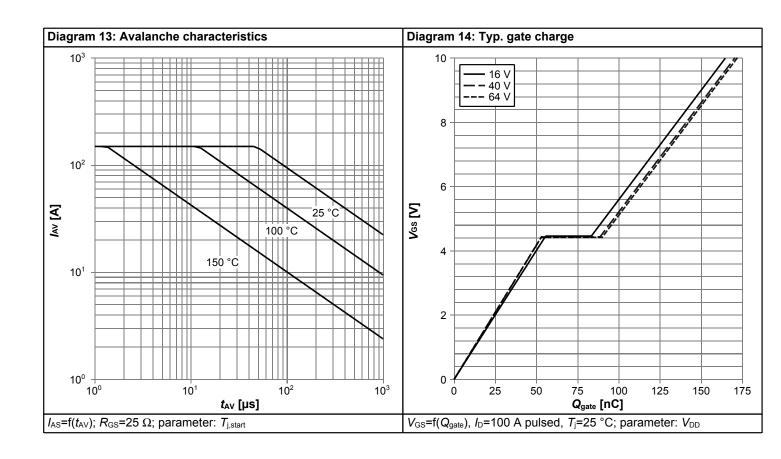


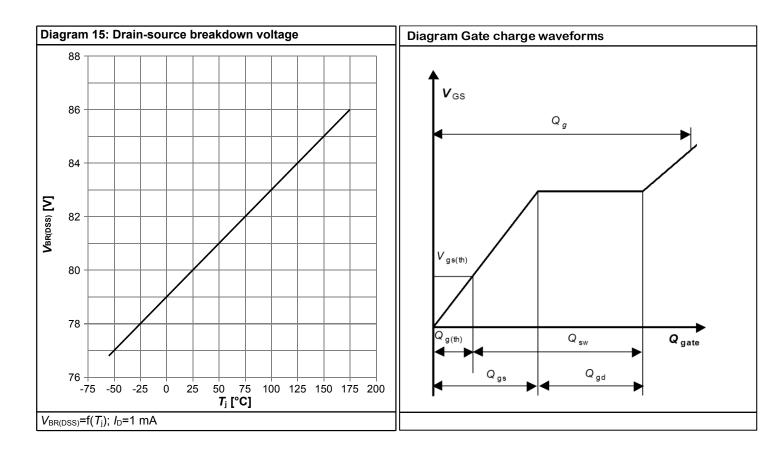














5 Package Outlines

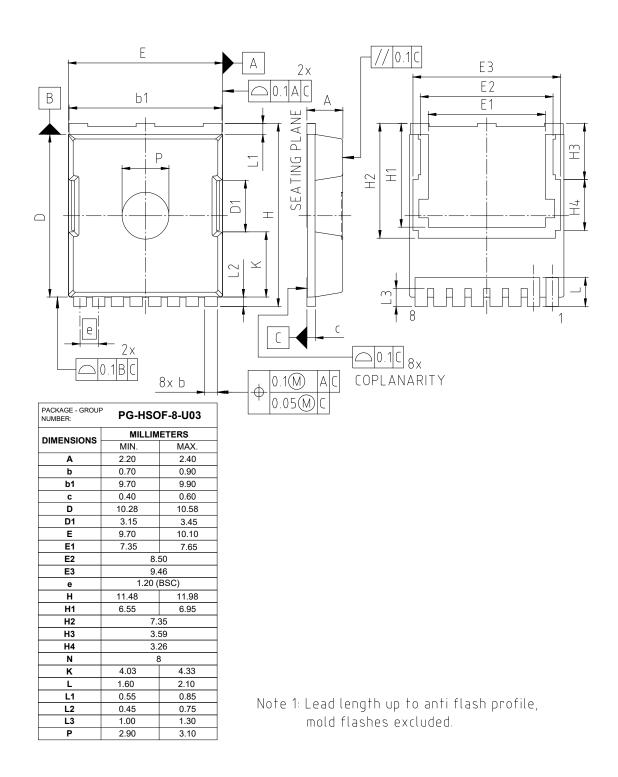


Figure 1 Outline PG-HSOF-8, dimensions in mm



Revision History

IPT012N08NF2S

Revision: 2022-08-08, Rev. 2.1

Previous Revision

1 Towns of T							
Revision	Date Subjects (major changes since last revision)						
2.0	2022-07-20	Release of final version					
2.1	2022-08-08	Update current for Rds(on)					

Trademarks

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